

| Search Notes | Application/Control No. | Applicant(s)/Patent under Reexamination |
|---------------|-------------------------|-----------------------------------------|
| | 09/274,015 | HEBERT ET AL. |
| Examiner | Art Unit | |
| EDMUND H. LEE | 1732 | |

SEARCHED

| INTERFERENCE SEARCHED | | | |
|------------------------------|----------|----------|----------|
| Class | Subclass | Date | Examiner |
| 264 | 255 | 2/6/2006 | EHL |
| | 275 | | |
| | 279.1 | | |
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